

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10565106	HAN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	M. Lee	2622

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
348	515, 518, 484	9/15/08	ml

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
east	9/15/08	ml

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

	/M. Lee/ Primary Examiner. Art Unit 2622
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